

# Broadband spectral measurements of diffuse optical properties by an integrating sphere instrument at the National Institute of Standards and Technology

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## ABSTRACT

Diffuse materials that approximate the optical properties of human tissue are commonly used as phantoms. In order to use the phantoms in a manner that provides consistent results relative to independent measurements, the optical properties need to be tied to a physics-based scale. Such a scale is needed for volume scattering of diffuse materials and this is currently being addressed by the development of a sphere based optical scattering reference instrument at the National Institute of Standards and Technology (NIST). Previous work towards that goal was constrained to the use of several laser lines at discrete wavelengths. Current work has expanded the spectral range for contiguous coverage. Here we report measurement results of the optical properties of solid phantoms, using two different base materials, acquired using NIST's diffuse optical properties reference instrument with visible or near infrared broadband illumination. The measurements of diffuse hemispherical reflectance and transmittance are analyzed using a custom inversion algorithm of the adding-doubling routine, and the expanded uncertainties on the results are provided. The broadband diffuse optical properties measured with the improved system agree to within the estimated uncertainty of the discrete measurements from two other institutes using alternative methods. This work expands the capabilities of the facility and can provide services for a wider range of applications.

**Keywords:** solid biomedical phantoms, integrating sphere, adding doubling, uncertainty budget, absorption coefficient, scattering coefficient, turbidity, broadband illumination.

## 1. INTRODUCTION

Biological phantoms are made of a mixture of scattering and absorbing materials in a liquid or in solid matrix and are used to mimic the optical properties of tissues in the development, characterization and maintenance of biomedical optical instruments. Scales for reflectance and transmittance are maintained by the National Institute of Standards and Technology (NIST). Such a scale is needed for volume scattering of diffuse materials and this need is currently being addressed by the development of an integrating sphere optical scattering reference instrument at NIST. The basic system and methods have been described in previous papers<sup>1,2</sup> and this paper presents the recent upgrade of the system to allow for broadband measurements of the absorption coefficient  $\mu_a$  and the reduced scattering coefficient  $\mu'_s$  in the visible range. Measurements of the optical properties of two types of solid biomedical phantoms are reported. The results are compared to measurements using time-domain measurement techniques.

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## 2. MATERIAL AND METHODS

Two types of solid samples were measured. A polyurethane-based sample was provided by the Institut National d'Optique (INO, Quebec, Canada). The base material was mixed with titanium dioxide ( $\text{TiO}_2$ ) powder to adjust  $\mu'_s$  and with carbon black to adjust  $\mu_a$ . The lateral dimensions of the INO sample were 100 mm square with a nominal thickness  $d=7$  mm (measured thickness  $d=7.11$  mm; uncertainty on  $d = 0.01$  mm). The surface aspect of the sample slab was non-specular due to machining by INO. The nominal optical properties were  $\mu_a=0.01 \text{ mm}^{-1}$  and  $\mu'_s=1 \text{ mm}^{-1}$  at  $\lambda=800$  nm (Fig. 1a).

Three polydimethylsiloxane (PDMS) samples with different concentration of added  $\text{TiO}_2$  (2, 1 and 0.5 g/kg) were built at NIST. The samples were molded using plastic Petri dishes. Their diameter was 87 mm and their nominal thickness was  $d = 5$  mm (measured thickness  $d = 4.85$  mm for  $\text{TiO}_2 = 0.2\%$ ,  $d = 4.29$  mm for  $\text{TiO}_2 = 0.1\%$ ,  $d = 4.32$  mm for  $\text{TiO}_2=0.05\%$ ;  $k = 1$  uncertainty on  $d = 0.01$  mm). The samples faces were specular (Fig. 1b).



(a) (b)  
Figure 1: INO samples (a) and PDMS samples (b).

### 2.1 Integrating Sphere Optical Scattering Instrument

Figure 2 shows the experimental setup for the measurement of the optical properties of the samples. Two types of illumination are possible: one using a laser line from one of three options (HeNe laser:  $\lambda=543$  nm,  $\lambda=632$  nm; laser diode:  $\lambda=785$  nm) and the other using a laser driven light source (LDLS, EQ 1500, Energetiq Technology Inc., MA, USA; broadband from 170 nm to 2100 nm). When down, a folding mirror FM allows the laser beam to reach the sample S. When FM is up, the broadband illumination of the sample is allowed.

The chosen laser beam (others being blocked by manual light shutter  $\text{LS}_1$ ,  $\text{LS}_2$  or  $\text{LS}_3$ ) is directed toward the sample by a set of mirrors ( $\text{M}_1$ ,  $\text{M}_2$ ,  $\text{M}_3$ ) and dichroic mirrors ( $\text{DM}_1$ ,  $\text{DM}_2$ ). The polarization of the laser beam is controlled by a polarizer P in front of a beam splitter  $\text{BS}_1$ . A portion of the beam power is detected by a photo-diode  $\text{D}_1$  while the remaining portion of the beam power is normal-incident to the front face of the sample set at the sample port of an integrating sphere. The sphere is rotated  $180^\circ$  to measure the transmittance of the sample. The signal of the corresponding diffuse reflectance or total transmittance of the sample are detected by the photo-diodes  $\text{D}_2$ . Two current-voltage amplifiers ( $\text{CV}_1$ ,  $\text{CV}_2$ ) convert the photo-currents to voltages acquired by a data acquisition board (DAQ).

Broadband illumination from the LDLS is collimated by  $\text{C}_1$  (biconvex lens, focal length  $f=30$  mm) and the beam is converged to the tip of a fiber  $\text{OF}_1$  by a parabolic mirror PM. At the output of the fiber, the beam is collimated by  $\text{C}_2$  (biconvex lens, focal length  $f=25$  mm) and directed by FM to a beam splitter  $\text{BS}_2$  that divert a portion of the beam to the tip of a fiber  $\text{OF}_2$  followed by a spectrometer  $\text{SM}_1$  for reference purposes. Again, the remaining part of the beam is normal incident to the front face of the sample, the reflectance (transmittance) signal is detected by a fiber  $\text{OF}_3$  followed by a spectrometer  $\text{SM}_2$ . The detection range of the spectrometer is 350 nm to 1050 nm.

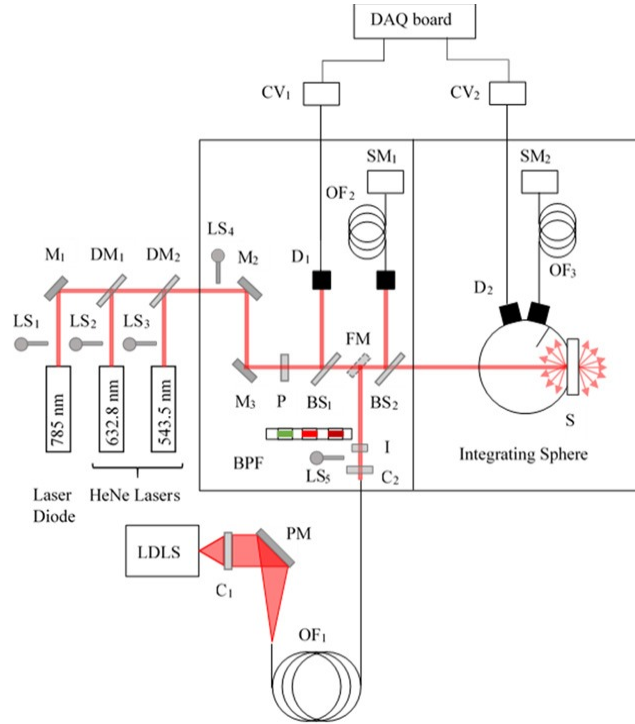


Figure 2: Schematic layout of the integrating sphere instrument; LDLS: laser-driven light source; LS<sub>1</sub>, LS<sub>2</sub>, LS<sub>3</sub>, LS<sub>4</sub> and LS<sub>5</sub>: light shutters; M<sub>1</sub>, M<sub>2</sub> and M<sub>3</sub>: mirrors; DM<sub>1</sub> and DM<sub>2</sub>: dichroic mirrors; P, Glan-Taylor linear polarizer; BS<sub>1</sub> and BS<sub>2</sub>: beam splitters; FM: folding mirror; C<sub>1</sub> and C<sub>2</sub>: collimators; I: iris; D<sub>1</sub> and D<sub>2</sub>: photodiodes; CV<sub>1</sub> and CV<sub>2</sub>: current-voltage amplifiers; DAQ: data acquisition board; OF<sub>1</sub>, OF<sub>2</sub> and OF<sub>3</sub>: optical fibers; SM<sub>1</sub> and SM<sub>2</sub>: spectrometers.

## 2.2 Measurements and data analysis

The measurements are based on the substitution procedure which requires to compare the reflectance of the sample to the reflectance of a standard (NIST traceable standard  $R_{\text{Std}}=99\%$ ) and the transmittance of the sample to the transmittance of a standard (100% transmittance standard, *i.e.*, no sample). The measured reflectance is expressed as

$$R_{\text{Meas}} = R_{\text{Std}} \frac{I_{\text{Sample}}}{I_{\text{Standard}}} \quad (1)$$

where  $I_i$  are the normalized intensities computed as the ratio of the measured voltages from the signal and reference channels ( $i = \text{Sample}$  when the sample at the sample port of the spheres,  $i = \text{Standard}$  when  $R_{\text{Std}}$  is at the sample port of the reflectance sphere). Similarly, the measured transmittance is

$$T_{\text{Meas}} = \frac{I_{\text{Sample}}}{I_{\text{Empty}}} \quad (2)$$

where  $I_i$  are the normalized intensities computed as the ratio of the measured voltages from the signal and reference channels ( $i = \text{Sample}$  when the sample at the sample port of the spheres,  $i = \text{Empty}$  when no sample is present and the sample port of both spheres are in contact). All signals are corrected for a background signal obtained when a light shutter LS<sub>4</sub> (laser illumination) or LS<sub>5</sub> (broadband illumination) is closed. The details on how to make these measurements can be found elsewhere.<sup>3,4</sup>

The data analysis is based on the adding-doubling (AD) algorithm by Prahl<sup>5</sup> which solves the radiative transfer equation (RTE) using  $\mu_a$ , the scattering coefficient  $\mu_s$ , the thickness of the samples  $d$ , the anisotropy scattering parameter  $g$  and the index of refraction of the bulk material  $n$  as inputs. AD computes the total

reflectance and transmittance of a thin layer of material under the assumption of single scattering events (for which a solution of the RTE exists) and computes the total reflectance and transmittance of the sample by successively adding/doubling the values until the thickness of the sample is reached. The inversion procedure uses the measured voltages, the geometrical parameters of the spheres,  $d$ ,  $n$  and  $g$  are input values to compute  $\mu_a$  and  $\mu'_s = (1 - g)\mu_s$  as well as the total uncertainty budget. The inversion procedure was previously described in Ref.[1].

### 3. RESULTS

#### 3.1 Polyurethane sample

Figure 3 presents the measurements of  $\mu_a$  and  $\mu'_s$  for  $\lambda = 450$  nm to 850 nm. The values are compared to measurements made by INO at  $\lambda = 475, 540, 543, 630, 632, 780, 805$  and 850 nm using a time-domain transmittance measurement coupled to an analysis procedure based on Monte-Carlo simulations.<sup>6</sup> The uncertainty on the INO results were estimated using values from Ref.[6] that were computed for different samples at  $\lambda = 600$  nm. The results in Fig. 3a and 3b are presented with a coverage factor  $k = 2$  ( $2 \times \sigma$  error bars). There is a overlap in the results between NIST and INO over the wavelength range for both  $\mu_a$  and  $\mu'_s$  within the error bar at  $k = 2$ . Typical uncertainty values for the integrating sphere instrument are 5% on  $\mu_a$ , 12% on  $\mu'_s$  compared to 11% on  $\mu_a$ , 7% on  $\mu'_s$  for the INO results. Table 1 summarizes the results by INO and our results at  $\lambda = [475, 540, 543, 630, 632, 780, 805, 850]$  nm].

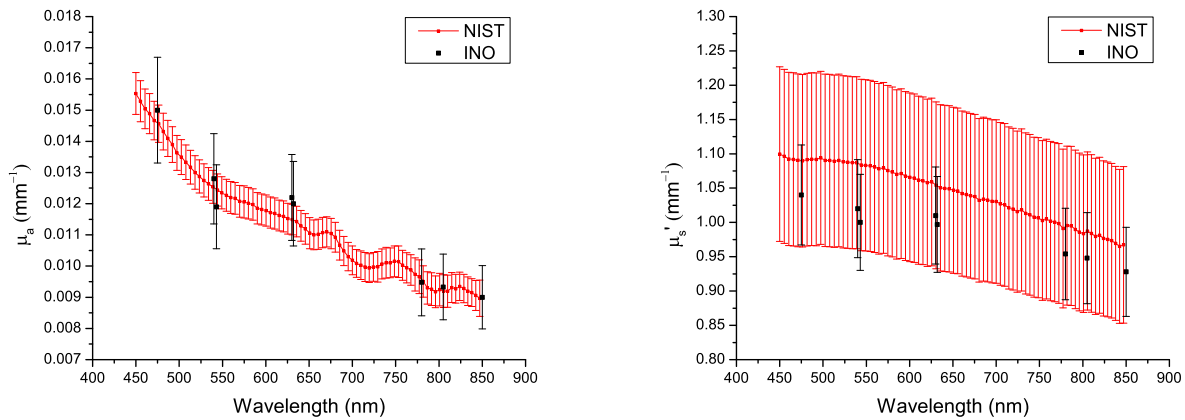


Figure 3: Broadband measurements of the absorption coefficient  $\mu_a$  and the reduced scattering coefficient  $\mu'_s$  for the INO sample using our single integrating sphere setup. The results are compared to the measurements by INO at  $\lambda = 475, 540, 543, 630, 632, 780, 805$  and 850 nm.

#### 3.2 PDMS samples

Figure 4 presents the measurements of  $\mu'_s$  for  $\lambda = 450$  nm to 850 nm for PDMS samples with  $\text{TiO}_2$  concentrations 0.05 %, 0.1 % and 0.2 %. The specular faces of the samples imply that for reflectance measurements at normal incidence, the specular reflectance is rejected through the entrance port of the integrating sphere. Hence, the measured reflectance is the diffuse reflectance and not the total reflectance expected by the adding-doubling algorithm. A correction for the Fresnel reflectance was introduced in a new version of our inversion algorithm to compensate for this. The values are compared to measurements made at the Physikalisch-Technische Bundesanstalt (PTB, Berlin, Germany) on thicker samples (about 12 mm thick) from the same batch at  $\lambda = 700, 750$  and 800 nm using a time domain measurement technique.<sup>7,8</sup> In this case the optical properties were derived from measurements of time-resolved diffuse transmittance or reflectance that were conducted independently using two systems based on fast detectors and time-correlated single photon counting. One system used a Ti:Sapphire

Table 1: Results and uncertainties ( $k = 2$ ) of:  $\mu_a$ , the absorption coefficient of the sample;  $\mu'_s$  the reduced scattering coefficient of the sample. The uncertainties on the INO results were estimated from measurements made on different samples at  $\lambda = 600$  nm as presented in Ref.[6].

$\lambda$ (nm)	$\mu_a \times 10^{-3}$ (mm $^{-1}$ )		$\mu'_s$ (mm $^{-1}$ )	
	INO	NIST	INO	NIST
475	$15.0 \pm 1.7$	$14.60 \pm 0.61$	$1.040 \pm 0.073$	$1.09 \pm 0.13$
540	$12.0 \pm 1.6$	$12.50 \pm 0.52$	$1.020 \pm 0.071$	$1.09 \pm 0.13$
543	$11.9 \pm 1.3$	$12.50 \pm 0.52$	$1.00 \pm 0.07$	$1.08 \pm 0.13$
630	$12.2 \pm 1.4$	$11.50 \pm 0.49$	$1.010 \pm 0.071$	$1.05 \pm 0.12$
632	$12.0 \pm 1.4$	$11.50 \pm 0.49$	$0.997 \pm 0.070$	$1.05 \pm 0.12$
780	$9.5 \pm 1.1$	$9.49 \pm 0.57$	$0.954 \pm 0.067$	$0.99 \pm 0.12$
805	$9.3 \pm 1.1$	$9.23 \pm 0.47$	$0.948 \pm 0.066$	$0.98 \pm 0.11$
850	$9.0 \pm 1.0$	$8.92 \pm 0.58$	$0.928 \pm 0.065$	$0.97 \pm 0.11$

laser, free-space optics and a microchannel plate photomultiplier. The second system employed a supercontinuum laser with acousto-optic filter, optical fibers to guide the light to and from the sample and a hybrid photodetector. The time resolution of these systems was about 35 ps and 125 ps, respectively. The fit procedure for obtaining  $\mu'_s$  and  $\mu_a$  was based on the white Monte Carlo method, with a database of photon time-of-flight distributions created for multiple  $\mu'_s$  values. The results presented here were obtained combining the data from both measurement systems.

The results in Fig. 4 are presented with a coverage factor  $k = 2$ . There is an overlap in the results between NIST and PTB. Typical uncertainty values on  $\mu'_s$  for NIST are about 10% compared to 5% to 8% for PTB. Table 4 summarizes the results by PTB and our results at  $\lambda = [700, 750, 800]$  nm].

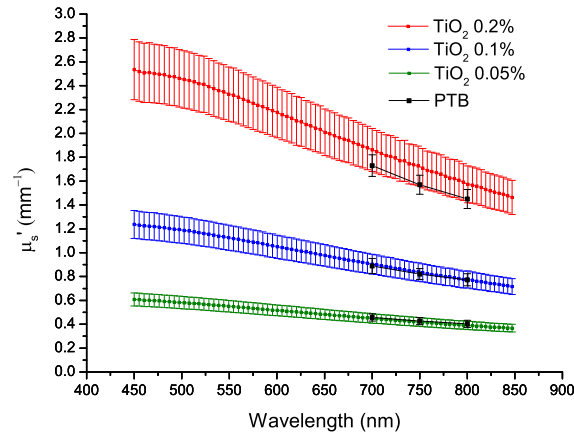


Figure 4: Broadband measurements of the reduced scattering coefficient  $\mu'_s$  for the PDMS samples using the integrating sphere setup. The results are compared to the measurements by PTB at  $\lambda = 700, 750$  and  $800$  nm.

#### 4. CONCLUSION

In this paper we studied four solid samples, one non-specular polyurethane-based sample from INO and three specular PDMS-based samples built at NIST. The absorption coefficient  $\mu_a$  of the INO sample and its reduced

Table 2: Results and uncertainties ( $k = 2$ ) of the reduced scattering coefficient  $\mu'_s$  of the PDMS samples as measured using the integrating sphere setup and the time domain measurement procedure used at PTB.

	$\lambda$ (nm)	$\mu'_s$ (mm <sup>-1</sup> )	
		PTB	NIST
TiO <sub>2</sub> = 0.05%	700	0.457 ± 0.030	0.449 ± 0.039
	750	0.427 ± 0.030	0.420 ± 0.037
	800	0.404 ± 0.030	0.391 ± 0.035
TiO <sub>2</sub> = 0.1%	700	0.888 ± 0.063	0.904 ± 0.083
	750	0.821 ± 0.046	0.838 ± 0.077
	800	0.773 ± 0.051	0.776 ± 0.071
TiO <sub>2</sub> = 0.2%	700	1.73 ± 0.09	1.86 ± 0.18
	750	1.57 ± 0.08	1.73 ± 0.17
	800	1.45 ± 0.08	1.57 ± 0.15

scattering coefficient  $\mu'_s$  were measured using NIST's integrating sphere optical scattering instrument from  $\lambda = 450$  nm to 850 nm. The results were compared to the ones at  $\lambda = 475, 540, 543, 630, 632, 780, 805$  and 850 nm provided by INO. There is an agreement between our results and the ones from INO within the error bar at  $k = 2$ . The uncertainty on our results were typically of 4% for  $\mu_a$  and 12% for  $\mu'_s$  compared to 11% and 7% respectively for INO. The reduced scattering coefficient  $\mu'_s$  of the PDMS samples were measured at NIST for  $\lambda = 450$  nm to 850 nm. Typical uncertainty values at  $k = 2$  on  $\mu'_s$  for NIST were of 10% compared to 5% to 8% for PTB for measurements made at  $\lambda = (700, 750 \text{ and } 800)$  nm. There is an agreement between our results and the ones from PTB within the uncertainty range. Future work in developing this facility will include an inter-comparison study of PDMS samples between measurements using the integrating sphere instrument and goniometric measurements of the reflectance and the transmittance under normal illumination made using the the NIST spectral tri-function automated reference reflectometer (STARR) facility coupled with an analysis using a Monte Carlo-based model.<sup>9,10</sup>

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